

Dual N-Channel 30-V (D-S) MOSFET

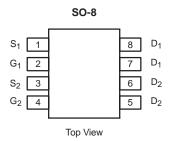
PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)	Q _g (Typ.)			
30	0.022 at V_{GS} = 10 V	6.8	15 nC			
	0.026 at V _{GS} = 4.5 V	6.0	15110			

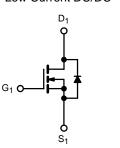
FEATURES

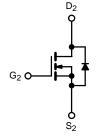
- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- 100 % UIS Tested
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Set Top Box
- Low Current DC/DC







N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25 \text{ °C}$, unless otherwise noted					
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	I _D	6.8 ^a 5.6 6.2 ^{b, c} 5.2 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	30		
Continuous Source-Drain Diode Current	$T_{C} = 25 \text{ °C}$ $T_{A} = 25 \text{ °C}$	I _S	2.25 1.48 ^{b, c} 5		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}			
Single Pulse Avalanche Energy		E _{AS}	1.25	mJ	
Maximum Power Dissipation	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	- P _D	2.7 1.77 1.78 ^{b, c} 1.14 ^{b, c}	w	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 10 s	R _{thJA}	58	70	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	38	45	0/11	

Notes:

a. Package limited, $T_C = 25$ °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 110 °C/W.

SPECIFICATIONS $T_J = 25 \text{ °C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V$, $I_{D} = 250 \mu A$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μΑ		32			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	iD = 230 μΛ		- 5.0		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zaro Cata Valtaga Drain Current	1	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	IDSS	V_{DS} = 30 V, V_{GS} = 0 V, T_{J} = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, V_{GS} = 10 V	10			А	
	Р	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$	0.022				
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4 \text{ A}$		0.026		Ω	
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		16		S	
Dynamic ^b							
Input Capacitance	C _{iss}			586		pF	
Output Capacitance	C _{oss}	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz		117			
Reverse Transfer Capacitance	C _{rss}			55			
Total Cata Charge	0	V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 5 A		15		nC	
Total Gate Charge	Qg			3.7	5.6		
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_D = 5 A		1.4			
Gate-Drain Charge	Q _{gd}			1.05			
Gate Resistance	Rg	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		55	100		
Turn-Off Delay Time	t _{d(off)}	${\rm I}_{\rm D}{\cong}5$ A, ${\rm V}_{\rm GEN}$ = 4.5 V, ${\rm R}_{\rm g}$ = 1 Ω		11	22		
Fall Time	t _f			8	16		
Turn-On Delay Time	t _{d(on)}			4	8	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		9	18	-	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ 5 A, V_GEN = 10 V, R_g = 1 Ω		10	20		
Fall Time	t _f			6	12		
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			2.25	٨	
Pulse Diode Forward Current	I _{SM}				24	A	
Body Diode Voltage	V _{SD}	$I_{S} = 2 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dl/dt = 100 A/µs, T _{.I} = 25 °C		4	8	nC	
Reverse Recovery Fall Time	t _a	$F = 5 A$, ui/ut = 100 A/µs, $T_{\rm J} = 25 C$		7	Ī		
Reverse Recovery Rise Time	t _b			4		ns	

Notes:

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.

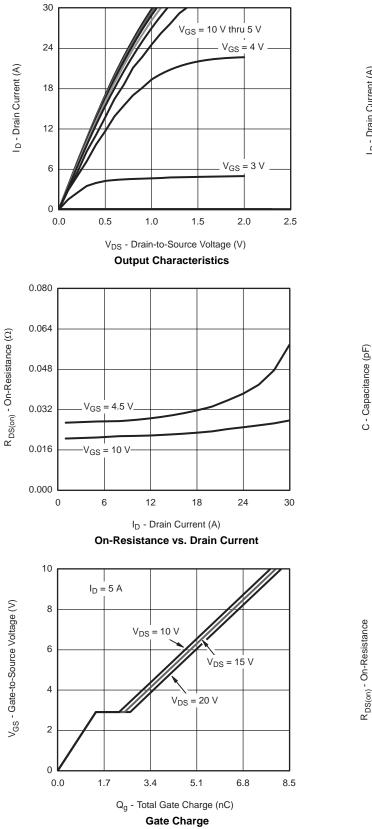
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

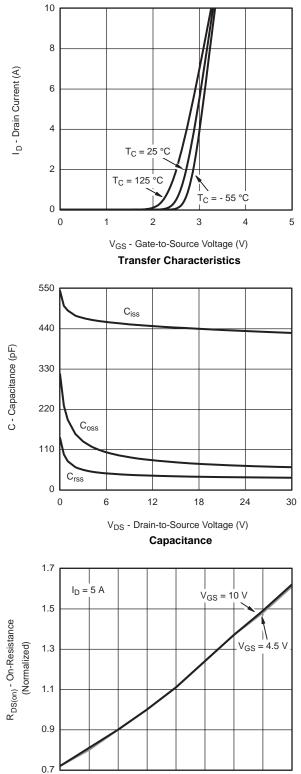
emi

IRF7313TR



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





 $T_J \mbox{ - Junction Temperature (°C)}$ On-Resistance vs. Junction Temperature

50

75

100

125 150

- 50

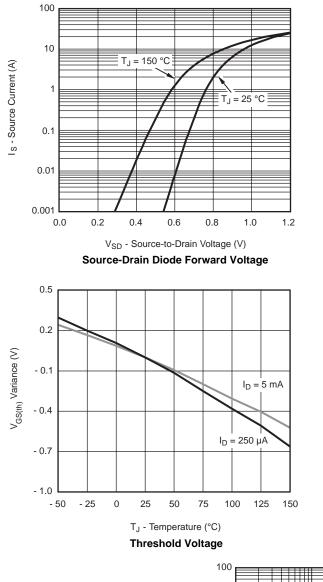
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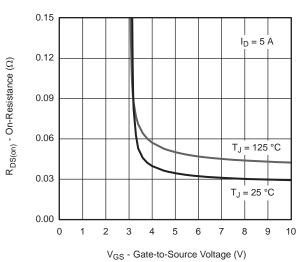
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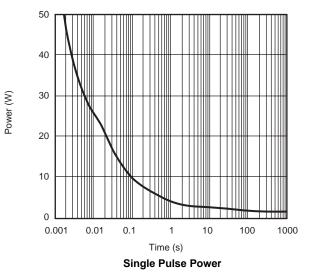


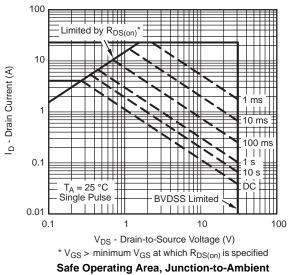
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





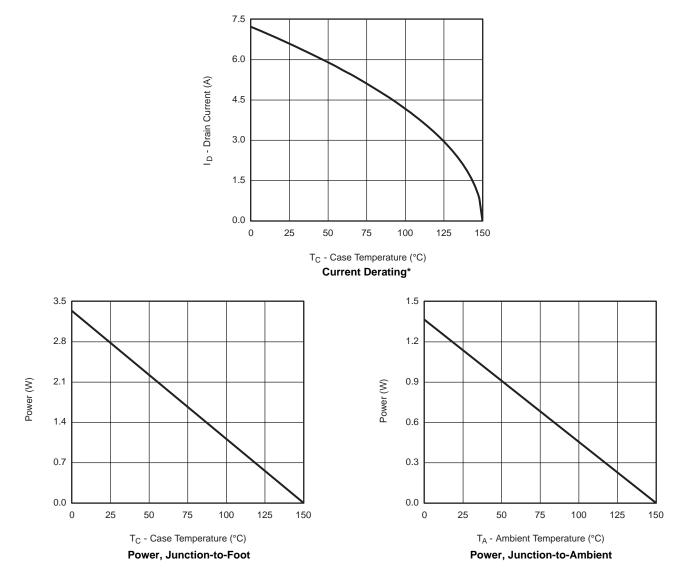
On-Resistance vs. Gate-to-Source Voltage







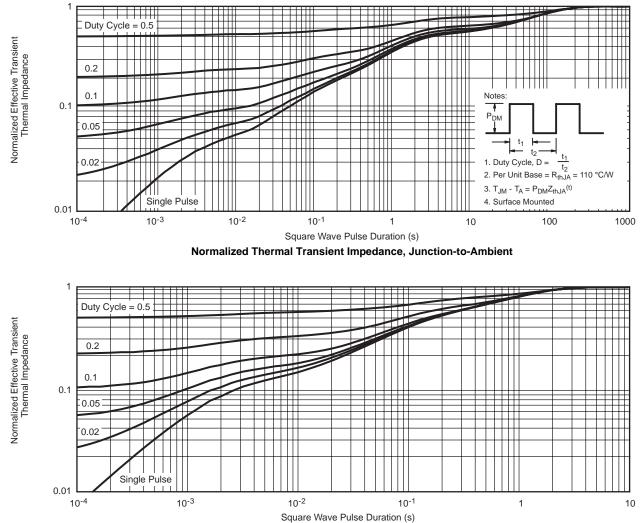
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* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

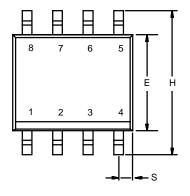


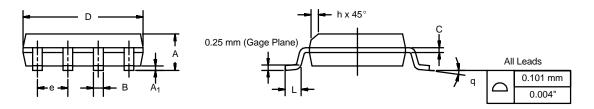
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

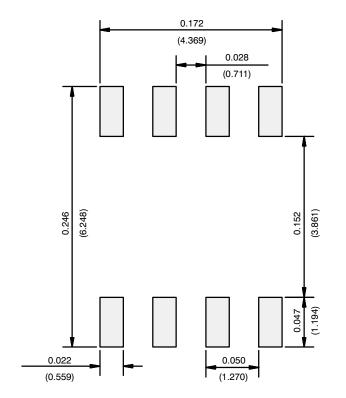




	MILLIMETERS		INC	HES		
DIM	Min	Мах	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	0.050 BSC		
н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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